Search Notes		

Application/Control No.		Applicant(s)/Patent under Reexamination	
	10/757,901	OIKAWA ET AL.	
	Examiner	Art Unit	
	Alain L. Bashore	1762	

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Class	Subclass	Date	Examiner

SEARCH (INCLUDING SEAF)
	DATE	EXMR
previous search updated	8/7/2006	АВ
EAST (attached)	8/7/2006	ab
		